

**Notice of References Cited**

Application/Control No.

09/319,222

Applicant(s)/Patent Under Reexam

Heed et al.

Examiner

Dennis-Doon Chow

Art Unit

2675

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	5,270,810	12/1993	Nishimura	358	98
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C	5,589,943	12/1996	Kozuki et al.	386	121
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**NON-PATENT DOCUMENTS**

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